

2000P15141

BOX AF

CERTIFICATION OF FACSIMILE TRANSMISSION

I hereby certify that this paper for Serial No. 09/923,720 is being facsimile transmitted to Technology Center 2800 of the Patent and Trademark Office at (703) 872-9319 on the date shown below.

Kyle H. Flindt
Kyle H. Flindt

January 13, 2004
Date

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IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

Applic. No. : 09/923,720 Confirmation No.:1125
Applicant : Frank Pietzschmann
Filed : August 6, 2001
Art Unit : 2829
Examiner : Emily Y. Chan
Title : Test Apparatus for Semiconductor Circuit
and Method of Testing Semiconductor
Circuits
Docket No. : 2000P15141
Customer No.: : 24131

A M E N D M E N T UNDER 37 CFR §1.116

Mail Stop AF Amendment
Hon. Commissioner for Patents
P.O. Box 1450
Alexandria, VA 22313-1450

S i r :

Responsive to the final Office Action dated October 14, 2003

kindly amend the above-identified application as follows:

Amendments to the Specification begin on page 3 of this
paper.

Appl. No. 09/923,720
Amdt. Dated January 13, 2004
Reply to Office Action of October 14, 2003

Amendments to the Claims are reflected in the listing of claims which begins on page 4 of this paper.

Amendments to the Drawings begin on page 14 of this paper and include both an attached replacement sheet and an annotated sheet showing changes.

Remarks/Arguments begin on page 15 of this paper.

An **Appendix** including amended drawing figures is attached following page 22 of this paper.